Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10531397	KLOSTERS ET AL.
Examiner	Art Unit
Flores Leon	2611

SEARCHED				
Class	Subclass	Date	Examiner	
375	354, 368	11/30/2007	LF	
370	509, 510	11/30/2007	LF	
327	141	11/30/2007	LF	

SEARCH NOTES				
Search Notes	Date	Examiner		
Consulted with SPE David Payne in regards to the patentability of the claims.	12/11/2007	LF		
Checked for possible double patenting.	11/29/2007	LF		
Searched in EAST & NPL (IEEE).	11/30/2007	LF		
Consulted with SPE David Payne in regards to the references used to reject the claims.	7/11/2008	LF		
Consulted with SPE David Payne in regards to the arguments.	12/19/2008	LF		

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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